Description:

The Yamada 250 Bright Light Inspection Tool is used for flaw detection of mirror-finished surfaces associated with processing of Si wafers, photomask blanks, magnetic disks, photomasks, pellicles and pelliclized photomasks.

With lighting of over 500,000 lux, this Inspection Tool allows easy observation of defects that are normally only distinguishable by veteran class inspectors. Since a halogen lamp is the light source, the color temperature is high: 3,400 deg. K. Because of this, irregularities of illumination and color are small enough so that sharp, stable lighting is always secured. In addition, the use of a cold mirror reduces the influence of heat to 1/2 to 1/3 that of a conventional aluminum mirror.

Flexibility is built in to the Yamada Bright Light Inspection Tool. The beam diameter is continuously variable from 30 to 150 mm by lens adjustment. Light control is done with a volume adjustment. An easy-access foot switch permits two-step change of high illumination and low illumination observation. A variety of accessories is available for various semiconductor equipment processing requirements.

Features:

- High intensity brightness at 500,000 lux
- Uniform illumination and color
- Cold mirror for redacted heat
- Multi-position stage
- Low profile defects (such as haze) detection
- Submicron defect detection
- Focused light to help in particle removal
- EPI spike inspection